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Assistant Commissioner for Patents
Washington, D.C. 20231

Re: U.S. Patent Application

Applicants: Tadao YOSHIDA, Keiji KANOTA, Hajime YANO, Hiroaki
OISHI, Junichi YOKOTA, Toyomi FUJINO

Our Ref.: 450100-02887

Dear Sir:

Enclosed are papers constituting the above patent application which is being filed under 37 C.F.R. 1.53 without a signed Declaration. Please accord a filing date and a serial number to such application and inform the undersigned thereof so that a signed Declaration and the surcharge required by 37 C.F.R. 1.16(e) may be duly filed.

Please address all correspondence to:

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Respectfully,

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Enclosures